



INFORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicants: J.D. Tobiason et al.

Attorney Docket No. MEIP122171

Application No.: 10/815,893

Group Art Unit: 3662

Filed: March 31, 2004

Title: SCALE FOR USE WITH A TRANSLATION AND ORIENTATION SENSING SYSTEM

U.S. PATENT DOCUMENTS

| *Examiner Initials | Cite No. | Document No. | Kind Code | Date (mm/dd/yyyy) | Name |
|--------------------|----------|--------------|-----------|-------------------|------------------|
| TT | U1 | 5,104,225 | A | 04/14/1992 | Masreliez |
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| TT | U3 | 6,642,506 | B1 | 11/04/2003 | Nahum et al. |
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FOREIGN PATENT DOCUMENTS

| *Examiner Initials | Cite No. | Document No. | Kind Code | Publication Date (mm/dd/yyyy) | Country | English Abstract Provided | Translation Provided |
|--------------------|----------|--------------|-----------|-------------------------------|---------|---------------------------|----------------------|
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None.

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OTHER INFORMATION
(Including Author, Title, Date, Pertinent Pages, Etc.)

| *Examiner Initial | Cite No. |
|-------------------|---|
| TT | O1 Dépret, B., et. al., "Characterization and Modelling of the Hollow Beam Produced by a Real Conical Lens," <i>Opt. Commun.</i> 211:31-38, October 1, 2002. |
| TT | O2 Reed, J.M., and S. Hutchinson, "Image Fusion and Subpixel Parameter Estimation for Automated Optical Inspection of Electronic Components," <i>IEEE Trans. Ind. Electron.</i> 43(3):346-354, June 1996. |

Examiner /Tri Ton/ **Date Considered** 05/25/2006

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

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